

•General Description

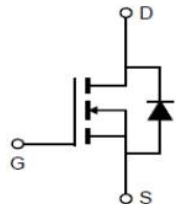


The Power MOSFET LH20N50A has the low $R_{DS(on)}$, low gate charge, fast switching and excellent avalanche characteristics. This device offers extremely fast and robust body diode, and is suitable for telecom and power supplies.

•Features

- Low Thermal Resistance
- Fast Switching
- High Input Resistance

•Application

- LED/LCD/PDP TV and monitor Lighting
- Power Supplies

	$V_{DS} = 500V$ $R_{DS(ON)} = 0.24\Omega$ $I_D = 20A$
 TO-220F	 TO-220

■ RoHS COMPLIANT

•Ordering Information:

Part number	LH20N50A	LH20N50A
Package	TO-220F	TO-220
Basic ordering unit (pcs)	1000	1000
Normal Package Material Ordering Code	LH20N50AF-T0220F-TU	LH20N50AT-T0220-TU
Halogen Free Ordering Code	LH20N50AF-T0220F-TU-HF	LH20N50AT-T0220-TU-HF

•Absolute Maximum Ratings (TC = 25°C)

PARAMETER	SYMBOL	Value	UNIT
Drain-Source Breakdown Voltage ¹	BV_{DSS}	500	V
Gate-Source Voltage	V_{GS}	± 30	V
Continuous Drain Current	I_D	20	A
		Figure 3	
Pulsed drain current ($T_C = 25^\circ C$, t_p limited by T_{jmax}) ²	I_{DM}	Figure 6	A
Single Pulse Avalanche Energy	E_{AS}	1500	mJ
Peak Diode Recovery dv/dt ³	dv/dt	5.0	V/nS
Power Dissipation($T_C=25^\circ C$)	P_D	TO-220F: 60	TO-220: 175
Maximum Temperature for Soldering Leads at 0.063 in (1.6mm) from Case for 10 seconds. Packing Body for 10 seconds	T_L	300	$^\circ C$
	T_{PAK}	260	
Junction Temperature	T_J	-55~+150	$^\circ C$
Storage Temperature	T_{STG}	-55~+150	$^\circ C$

●Electronic Characteristics

PARAMETER	SYMBOL	TEST CONDITION	MIN	TYP	MAX	UNIT
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{GS}=0V, I_D=250\mu A$	500	--	--	V
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	2.0	--	4.0	V
Drain-source On Resistance ³	$R_{DS(ON)}$	$V_{GS}=10V, I_D=10A$	--	0.24	0.3	Ω
Drain-Source Leakage Current	I_{DSS}	$V_{DS}=500V, V_{GS}=0V, T_J=25^\circ C$	--	--	1	μA
		$V_{DS}=400V, V_{GS}=0V, T_J=125^\circ C$	--	--	100	
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=\pm 30$	--	--	± 100	nA
Forward Transconductance ⁴	g_{fs}	$V_{DS}=15V, I_D=10A$	--	18	--	S
Input Capacitance	C_{iss}	$V_{GS}=0V,$ $V_{DS}=25V,$ $f=1.0MHz$	--	2670	--	pF
Output Capacitance	C_{oss}		--	35	--	
Reverse transfer Capacitance	C_{rss}		--	260	--	
Turn-On Delay Time	$T_d(on)$	$V_{DD}=250V,$ $I_D=20A,$ $V_{GS}=10V,$ $R_G=25\Omega$	--	35	--	ns
Rise Time	T_{rise}		--	75	--	
Turn -Off Delay Time	$T_d(off)$		--	165	--	
Fall Time	T_{fall}		--	85	--	
Total Gate Charge	Q_g	$I_D=20A,$ $V_{DS}=250V$ $V_{GS}=10V$	--	65	---	nC
Gate-to-Source Charge	Q_{gs}		--	14	--	
Gate-to-Drain Charge	Q_{gd}		--	24	---	
Continuous Diode Forward Current	I_S		--	--	20	A
Pulsed Diode Forward Current	I_{SM}		--	--	80	A
Diode Forward Voltage	V_{SD}	$T_J=25^\circ C, I_S=20A$ $V_{GS}=0V$	--	--	1.5	V
Reverse Recovery Time	t_{rr}	$I_f=I_S$ $di_f/dt=100A/\mu s$	--	320	--	ns
Reverse Recovery Charge	Q_{rr}		--	3.0	--	μC

●Thermal Characteristics

PARAMETER	SYMBOL	MAX		UNIT
		TO-220F	TO-220	
Thermal Resistance Junction-case	R_{thJC}	2.08	0.71	$^\circ C/W$
Thermal Resistance Junction-ambient	R_{thJA}	100	62	$^\circ C/W$

Notes:

- $T_J=25$ to $150^\circ C$
- Repetitive Rating: Pulse width limited by maximum junction temperature.
- $I_{SD} = 20A, di/dt < 100A/\mu s, T_J = 150^\circ C$
- Pulse Test : Pulse width $\leq 300\mu s$, Duty cycle ≤ 2

• Typical Characteristics

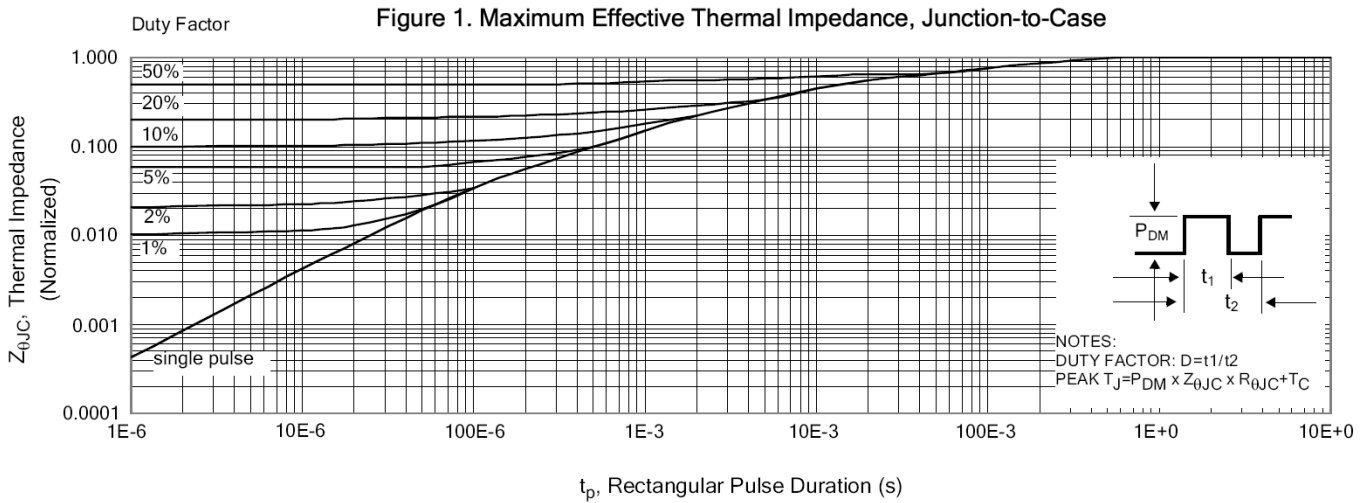


Figure 2. Maximum Power Dissipation vs Case Temperature

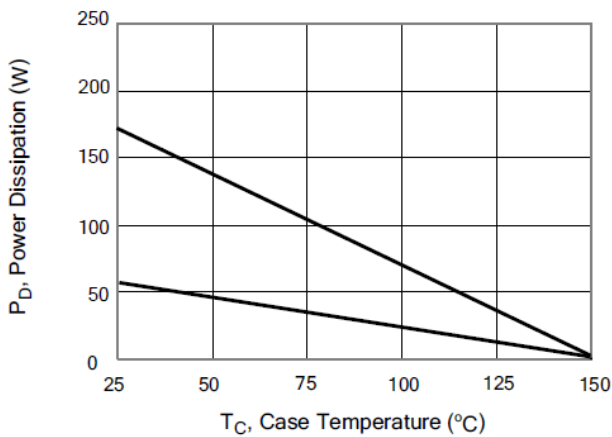


Figure 3. Maximum Continuous Drain Current vs Case Temperature

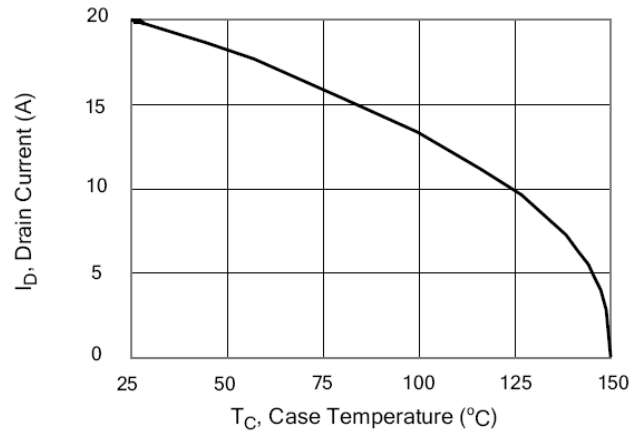


Figure 4. Typical Output Characteristics

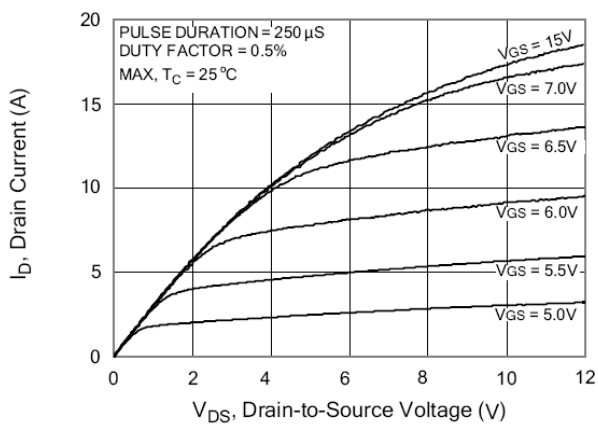
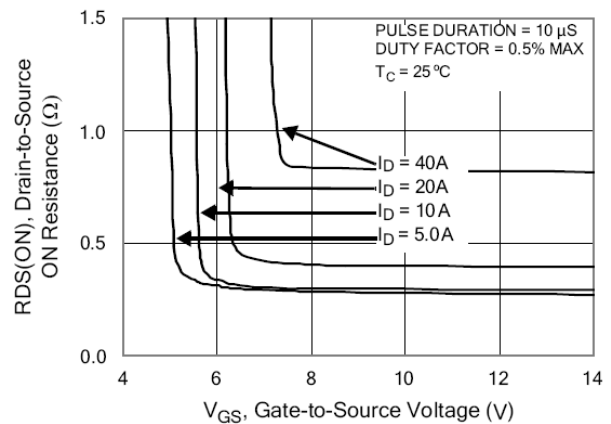


Figure 5. Typical Drain-to-Source ON Resistance vs Gate Voltage and Drain Current



• **Typical Characteristics(cont.)**

Figure 6. Maximum Peak Current Capability

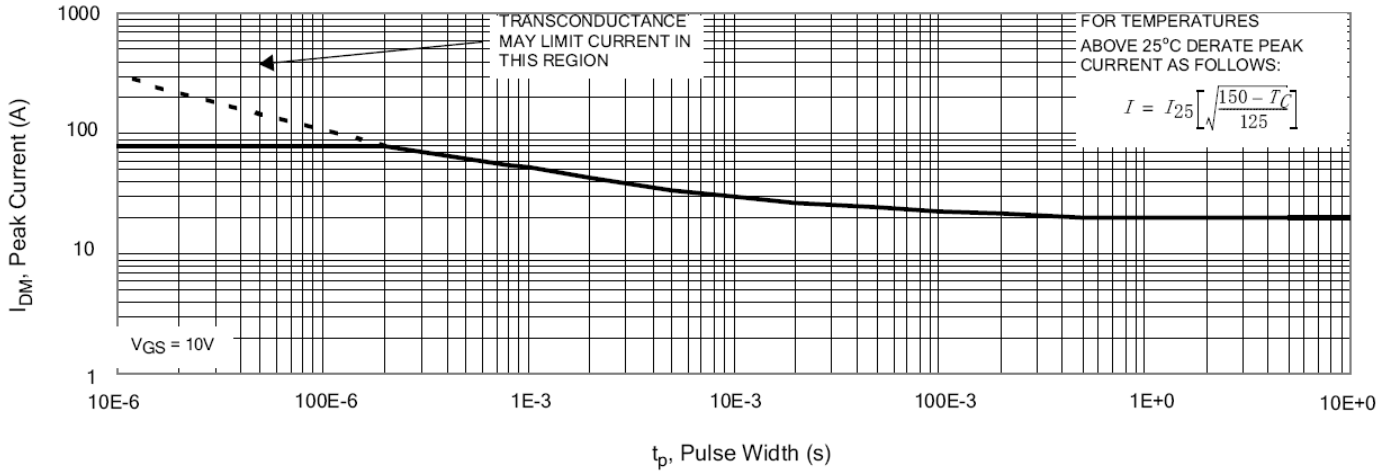


Figure 7. Typical Transfer Characteristics

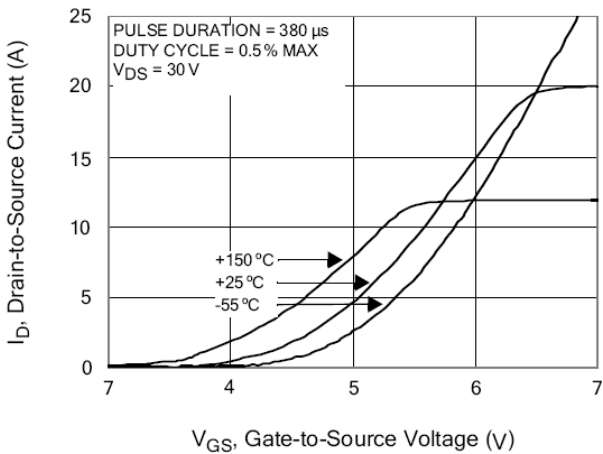


Figure 9. Typical Drain-to-Source ON Resistance vs Drain Current

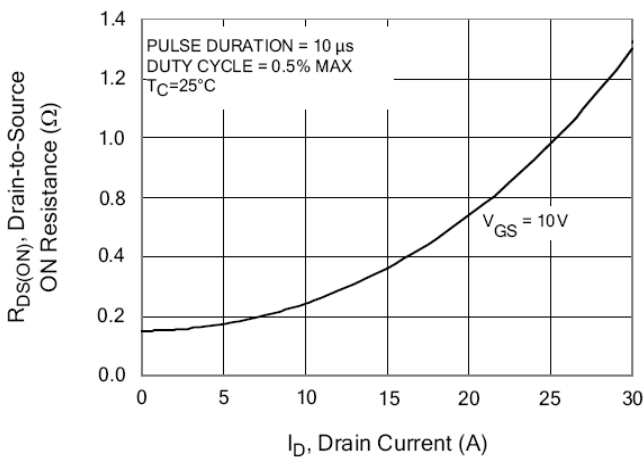


Figure 8. Unclamped Inductive Switching Capability

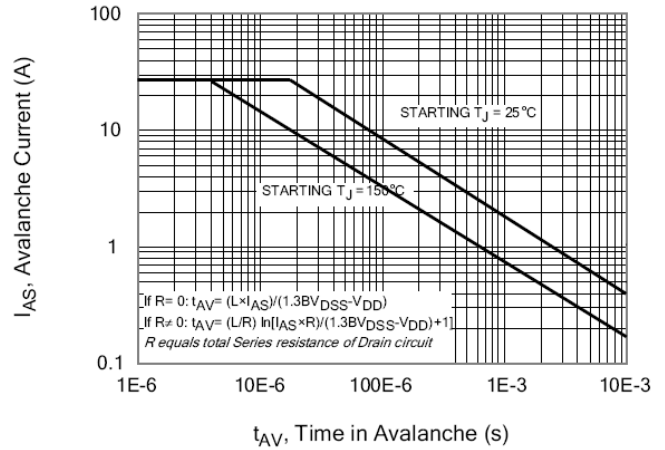
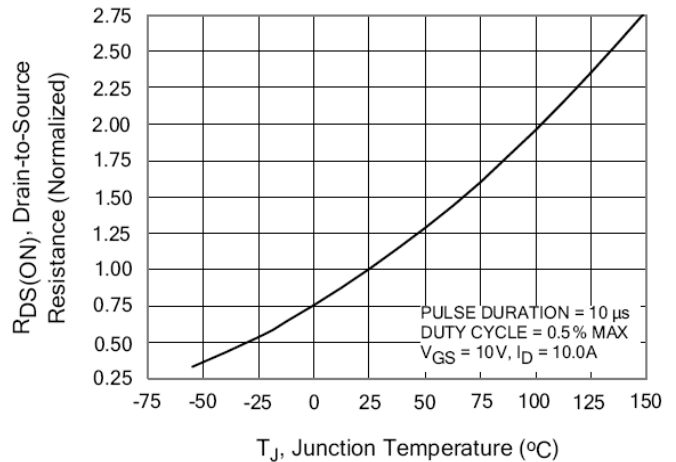


Figure 10. Typical Drain-to-Source ON Resistance vs Junction Temperature



● **Typical Characteristics(cont.)**

Figure 11. Typical Breakdown Voltage vs Junction Temperature

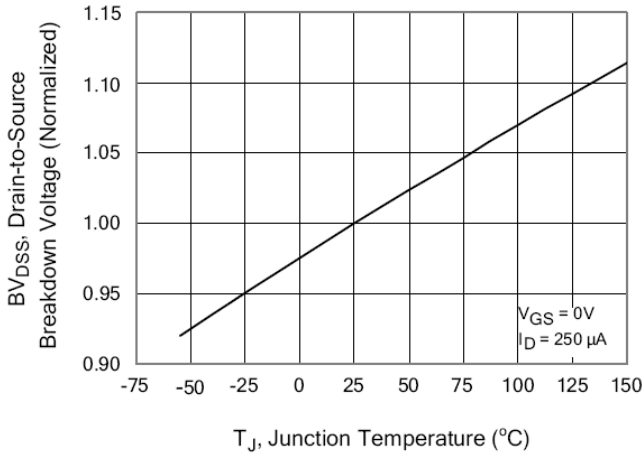


Figure 12. Typical Threshold Voltage vs Junction Temperature

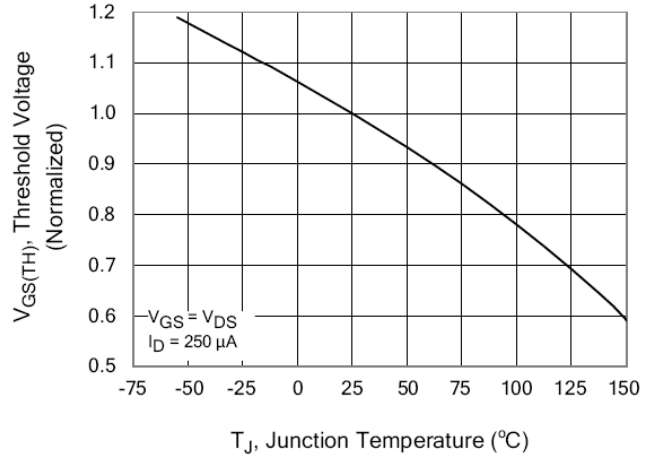


Figure 13. Maximum Forward Bias Safe Operating Area

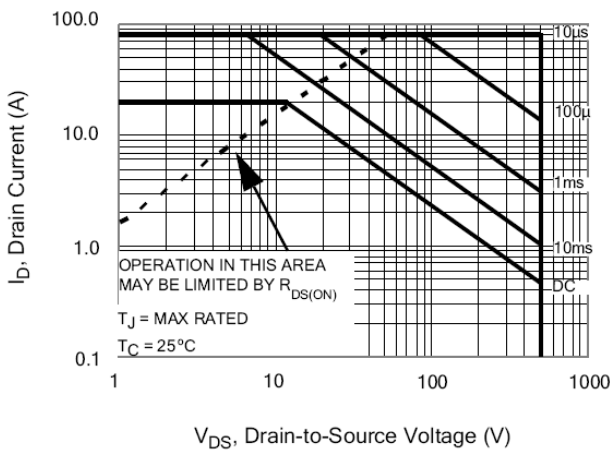


Figure 14. Typical Capacitance vs Drain-to-Source Voltage

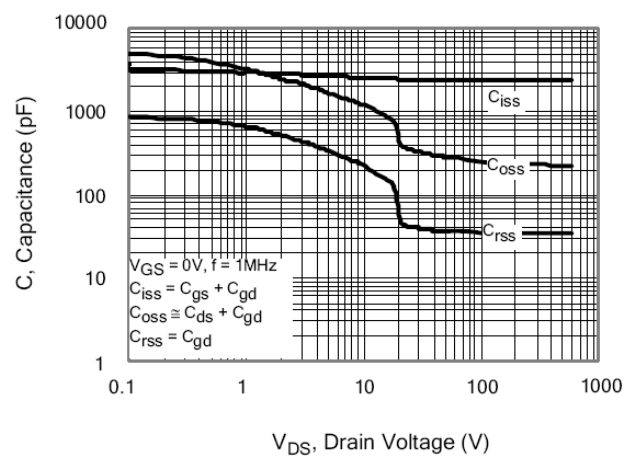


Figure 15. Typical Gate Charge vs Gate-to-Source Voltage

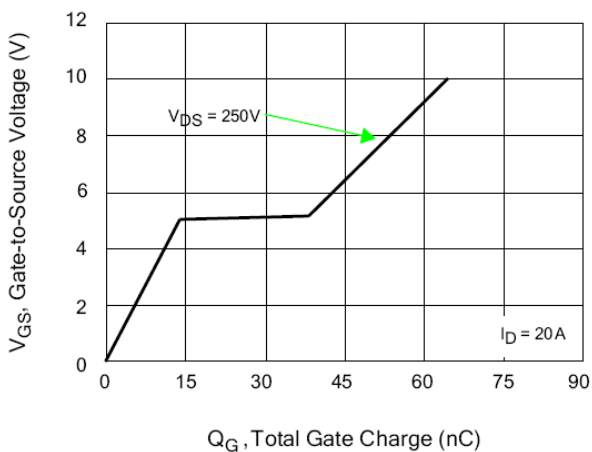
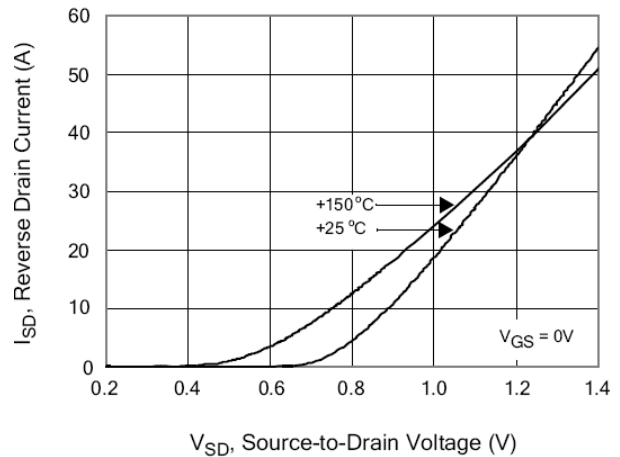


Figure 16. Typical Body Diode Transfer Characteristics



● Test Circuits & Waveforms

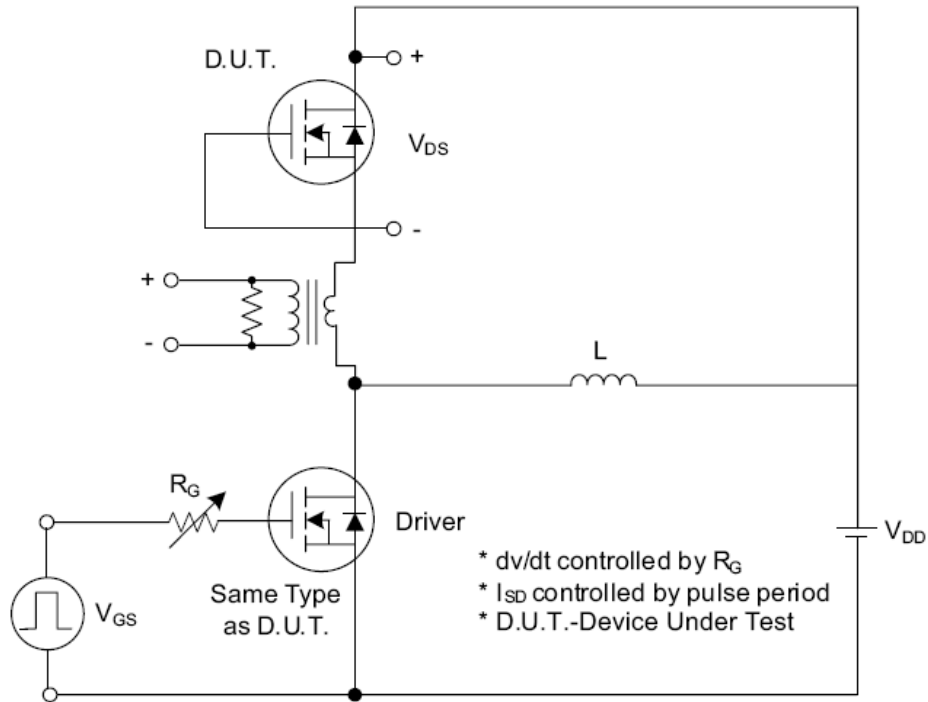


Fig. 1.1 Peak Diode Recovery dv/dt Test Circuit

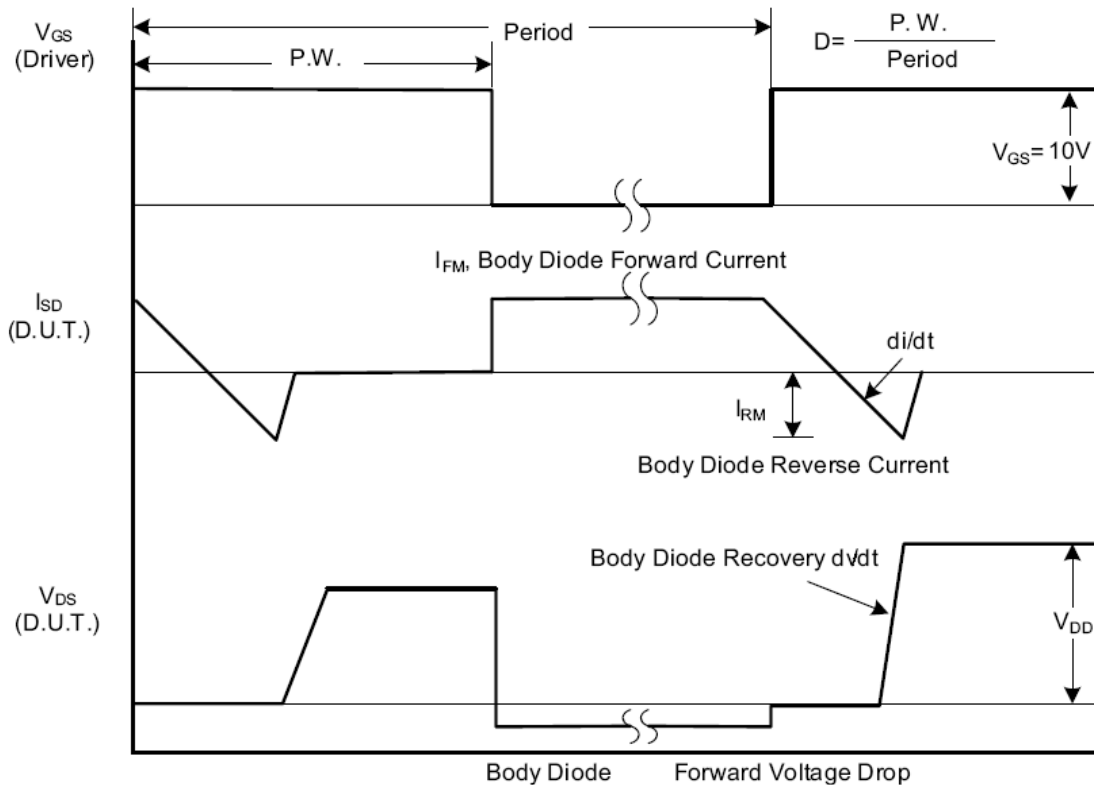


Fig. 1.2 Peak Diode Recovery dv/dt Waveforms

● **Test Circuits & Waveforms(cont.)**

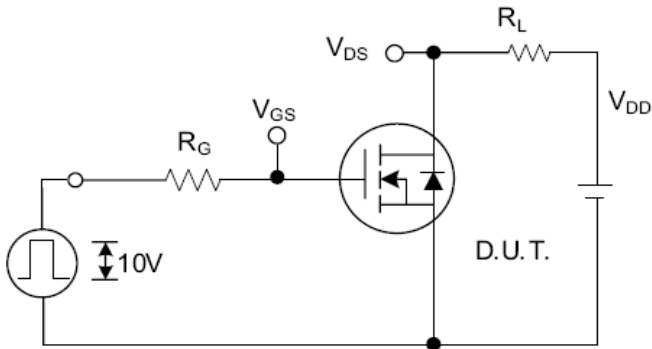


Fig. 2.1 Switching Test Circuit

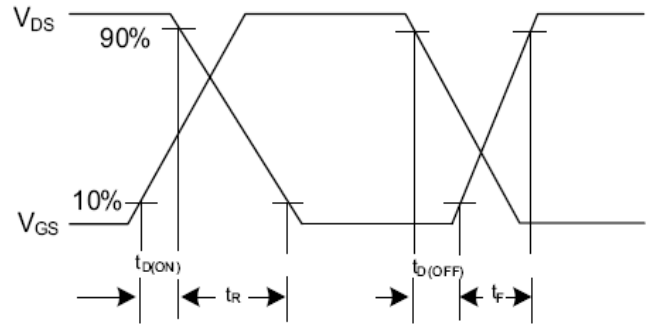


Fig. 2.2 Switching Waveforms

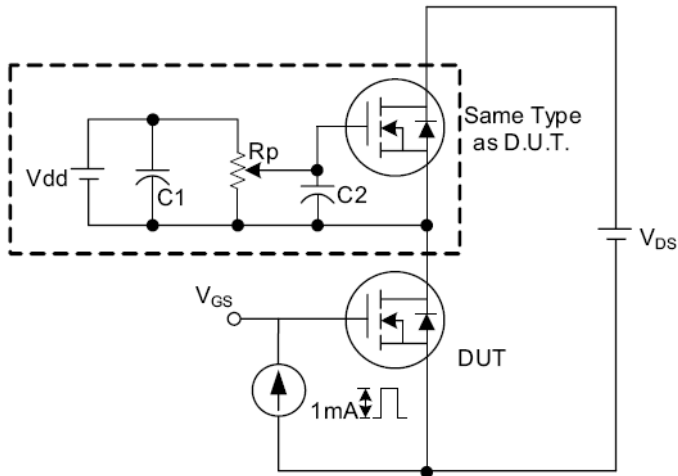


Fig. 3.1 Gate Charge Test Circuit

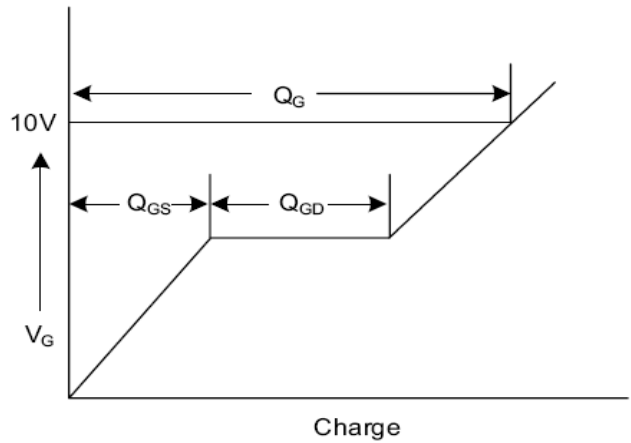


Fig. 3.2 Gate Charge Waveform

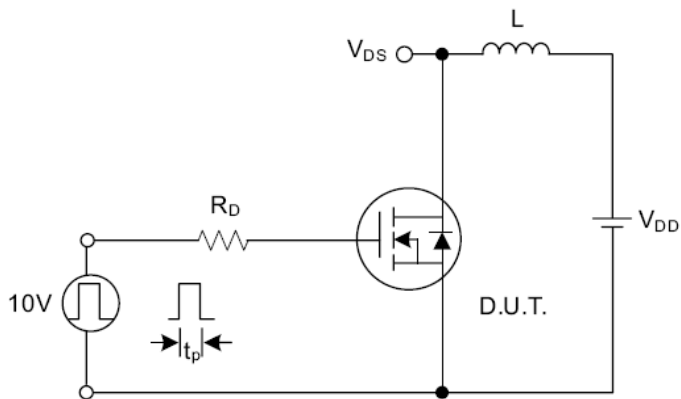


Fig. 4.1 Unclamped Inductive Switching Test Circuit

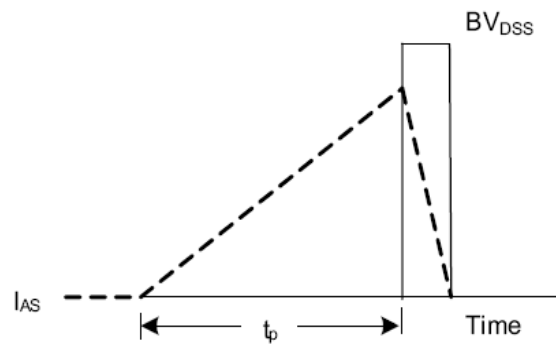
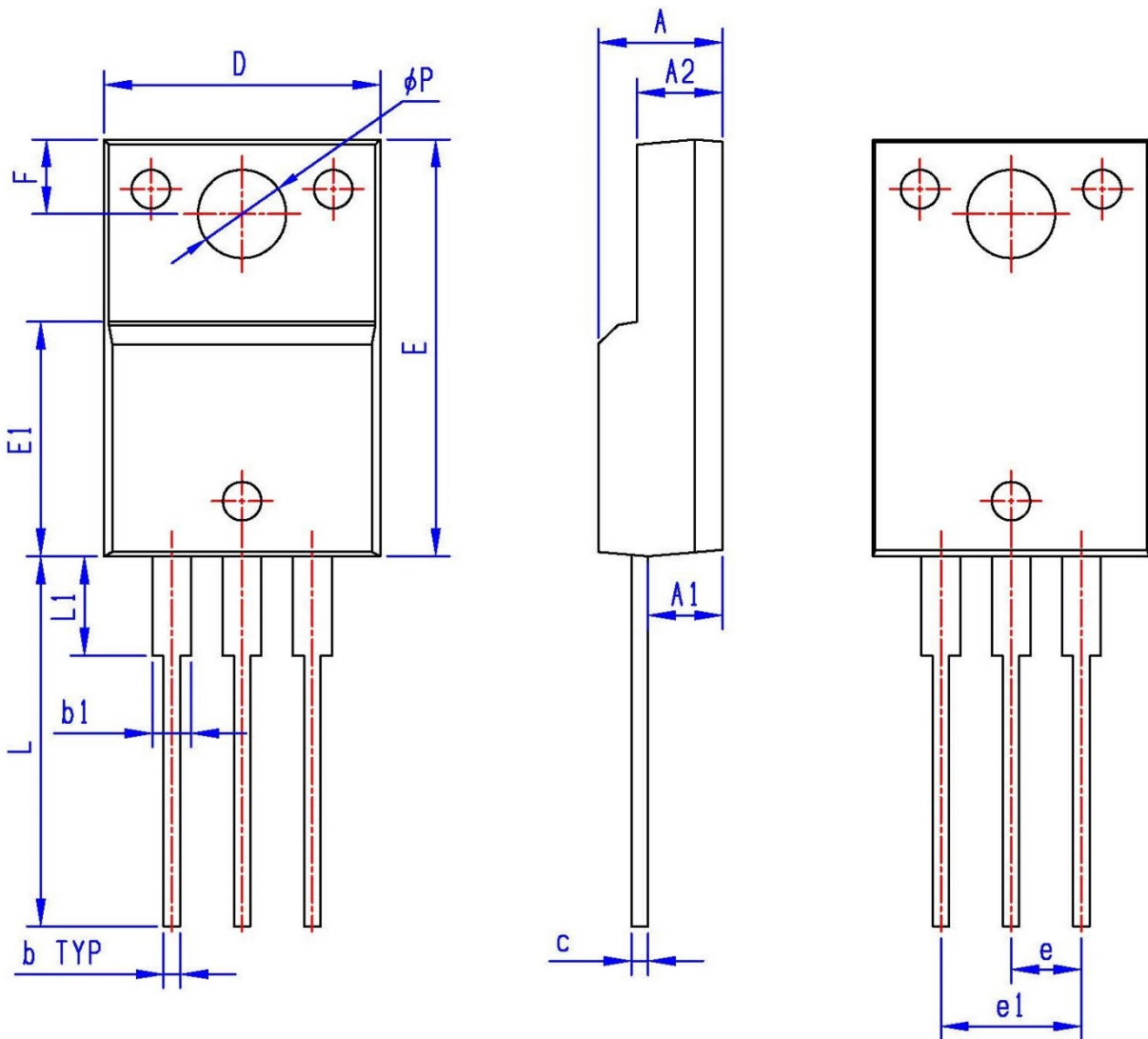


Fig. 4.2 Unclamped Inductive Switching Waveforms

●Dimensions (TO-220F)

UNIT:mm

SYMBOL	min	max	SYMBOL	min	max
A	4.20	4.80	E1	8.30	8.70
A1	2.50	2.90	e	2.40	2.70
A2	2.90	3.30	e1	4.95	5.25
b	0.40	0.80	F	2.50	2.90
b1	1.10	1.50	L	13.00	14.00
c	0.50	0.70	L1	3.00	4.00
D	9.80	10.60	∅P	2.90	3.50
E	14.60	15.60			



•Dimensions (TO-220)

UNIT:mm

SYMBOL	min	max	SYMBOL	min	max
A	4.25	4.85	B1	2.60	3.00
A1	2.30	3.00	e	2.40	2.70
A2	1.20	1.40	e1	4.95	5.25
b	0.60	0.90	L	12.60	14.40
b1	1.10	1.70	L1	2.40	4.00
c	0.40	0.70	∅P	3.50	3.90
D	9.80	10.60			
B	15.20	16.20			

